Application/Control No. Applicant(s)/Patent Under Reexamination MIYAMARU ET AL. Examiner Tanmay S Lele Applicant(s)/Patent Under Reexamination MIYAMARU ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,908,168	09-1975	McMahon	325/1
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			"
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2,103,043	02-1983	GB	Allman et al.	H04B 9/00
	0	JP 04-362,613	12-1992	JP	Atsuyoshi et al.	H05K 5/02
	Р	DE 4,233,721	04-1994	DE	Schwerer	H04B 01/38
	Q					
	R			-		
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.